



Test Setup and Configuration

- All the tests are logically grouped based on the input source requirement

 - WRITE
 - CLOCK - ADDR/CMD
- Quickly set up the test configuration by selecting a complete group or individual tests
- Flexible input source requirement, inputs are not hardwired to a particular Oscilloscope channel.



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Burst Detection

- Read / Write bursts are automatically detected for analysis purposes
- Several different techniques are used for Read/Write Burst Separation

 - irst Separation

 DQ/DQS phase alignment: DQ and DQS have different phase relationship in Read and Write bursts

 CS, Latency + DQ/DQS Phase Alignment: CS is used to quality the occurrence of a burst, followed by DQ/DS phase relationship to distinguish between ReadWrite

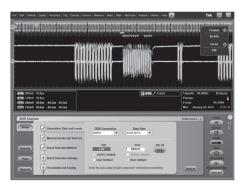
 Logic State + Burst latency: The command bus probed using the digital channels on the MSO is used to identify. Boat Multiple propagated by the command business.
 - identify Read/Write commands on the command bus are quality and distinguish Read and Write bursts
- Options are provided to adjust the levels to improve burst detection in systems with lower signal integrity



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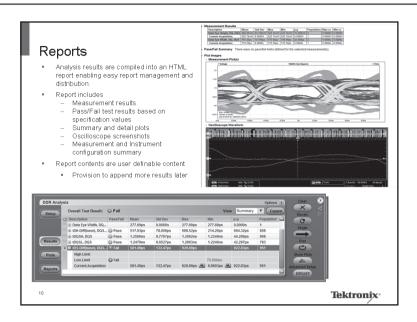
Burst Detection

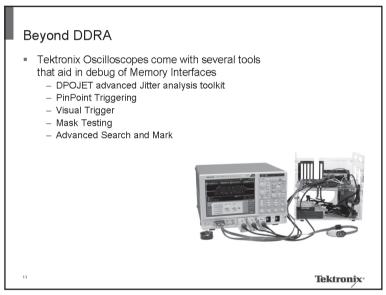
- Easily Identify, Mark & Measure all Read / Write bursts
 - Scroll through marked reads / writes across the entire waveform record
 - Measurements performed on ALL Reads/writes within an acquisition

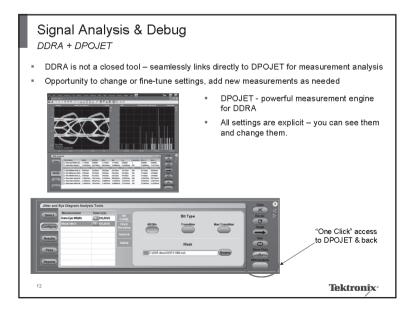


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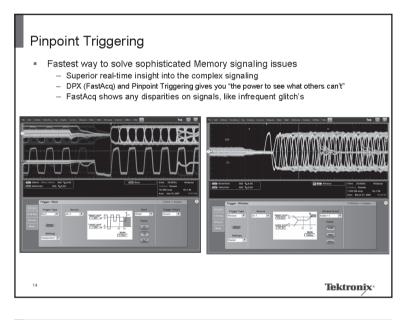


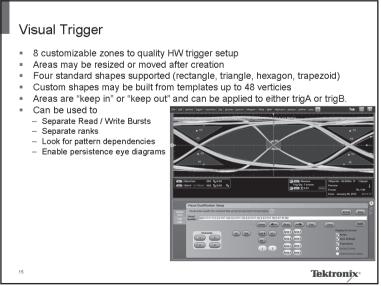




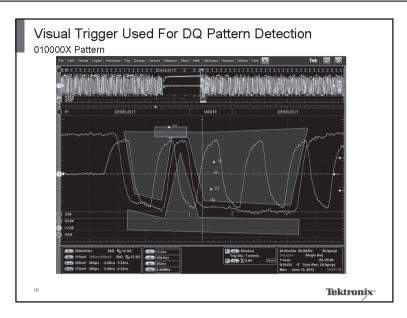


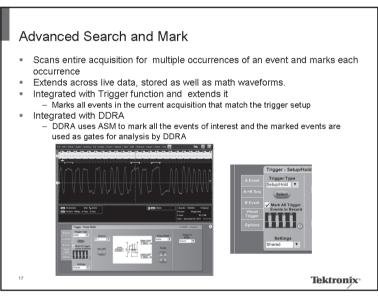


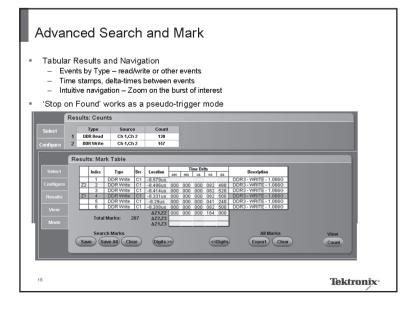














Memory Probing

- Computer Systems use standardized DIMM's for which several probing solutions are available
- Memory in Embedded Designs is usually directly mounted on the PCB.
- Memory Components use BGA or PoP Packages
 - Reduces the parasitics, enabling performance at higher speeds
 - Mandate from JEDEC
- Probing a BGA or PoP package is Difficult
 - Unable to probe at the Balls of the Device
 - Probing at a connector, trace, or a via is not the same as probing at the device
 - Not a true representation of the signal

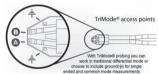


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TriMode Probing

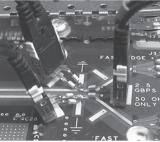
- TriMode, with a single probe-DUT connection, allows:
 - Traditional differential measurements: V+ to V-
 - Independent single ended measurements on either input
 - V+ with respect to ground
 - V- with respect to ground
 - Direct common mode measurements: ((V+) + (V-))/2 with respect to
- Many standards require both differential and single-ended voltage limit measurements. Requires two separate probes - Until Now!





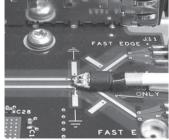
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Before and After



Before TriMode Probing

- 1 Probe for Differential 2 Probes for SE and Common Mode
- 1 Probe Soldered and Re-soldered 3 times 2 Probes for Common Mode



After TriMode Probing

1 Probe and 1 setup for Differential, SE and Common Mode

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Memory Component Interposers Provide easy access to signals of Interest Controller Impedance path with embedded resistor for good signal Integrity De-embed filters to remove effects of interposer tap trace SPICE model available upon request for simulation and analysis

-	SPICE Induel available upon request for simulation and ana		
	Memory Standard	Supported Form Factors	Interposer Types
	DDR2	- BGA	- Socketed Interposer - Direct Attach Interposer
	DDR3	- BGA	- Socketed Interposer - Direct Attach Interposer - MSO DIMM Interposer - Instrumented DIMM
	DDR4	- BGA	- Socketed Interposer - Direct Attach Perimeter Interposer - MSO DIMM Interposer - Instrumented DIMM
	LPDDR2	- BGA - PoP	- Socketed Interposer - PoP Interposer
	LPDDR3	- BGA - PoP	- Socketed Interposer - PoP Interposer
	GDDR5	- BGA	- Socketed Interposer - Direct Attach Interposer
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De-embedding

- In order to remove the effects on the Interposer, probe tips and probes de-embedding must be considered.
- De-embedding filters will available for the interposers upon request.
 These de-embedding filters are developed assuming nominal values
- For more accurate characterization for a particular setup SDLA visualizer for Real time scopes can be used



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Memory Interface Digital Validation

Measure the digital logic state and cycle based timing characteristics for diagnostic and troubleshooting purposes





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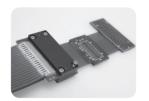
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DDR4 Memory Component Interposers

- MCI's are used for probing signals from individual Memory Components
- Comes with a Custom Socket that needs to be soldered to Target system
- Quickly swap TLA & oscilloscope interposers on the same target. Quickly move interposers to different target.
- No special footprints or special routing requirements
- Memory Component Interposer Types
 - Logic Analyzer and Oscilloscope
 - Direct Attach or Socketed interposers
 - x4/x8 and x16 Memory Component types







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DDR4 ACC Interposers

- Protocol / Execution Validation
 - DIMM and SODIMM Interposers
 - Targeted for protocol compliance analysis
 - Automated Setup
 - Use with Nexus Compliance Analysis S/W
 - Compatible with P6960HCD or NEX-PRB1XL





Sales University 2012 - Tektronix Confidential Course Title vx.x (Edit in View/Insert > Header and Footer)

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Introducing New DDR3/4 High Speed Interposer

Next Generation DDR3/4 Probing Technology

Gain Unprecedented Visibility Into Your DDR3/4 Signal Activity





DIMM Interposer

SODIMM Interposer

Collaborative design combining years of Logic Analyzer acquisition and DDR3 probing experience between Tektronix and Nexus Technology

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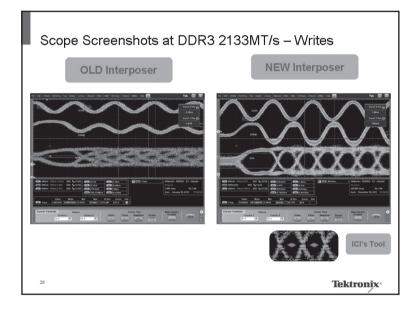


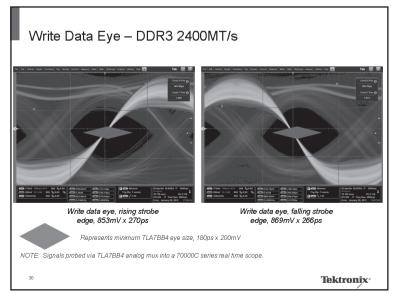
New DDR3/4 High Speed Interposer

Next Generation DDR3/4 Probing Technology

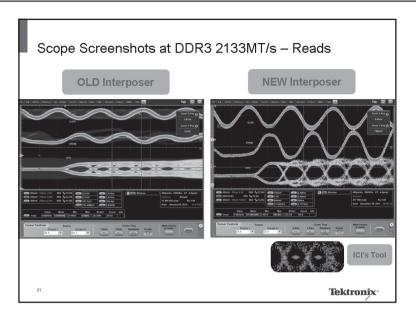
- Provides significant performance improvements to DDR3 probing
 - Integrates Tektronix ultra-high performance SiGe Hybrid ASIC technology
 - Compensation for platform trace loss on writes
- Improved interposer input impedance (5.2k to 0.73V)
 - Reduces load on target with minimal effect on bus
 - Provides an accurate representation of the signal on the target
- Enables probing DDR3/4 speeds at 2400MT/s and beyond
- Enables probing lower voltage signals on LVDDR3/4
- Interposers compatible with UDIMM, RDIMM, LRDIMM

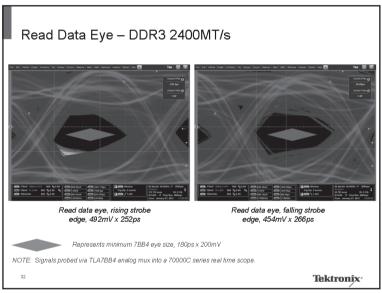
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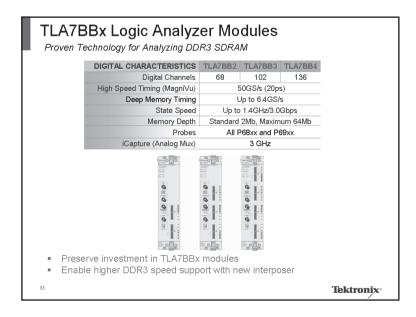




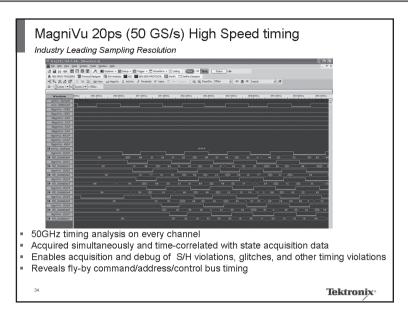


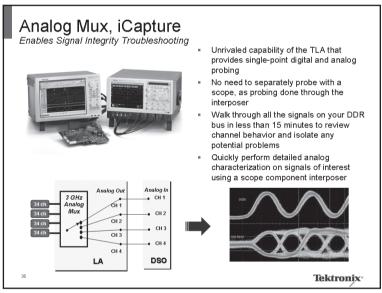


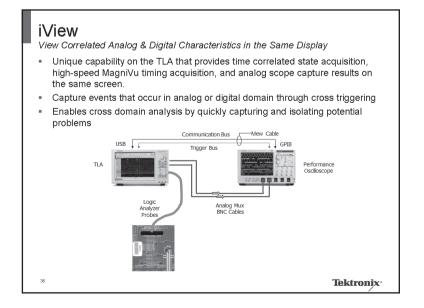


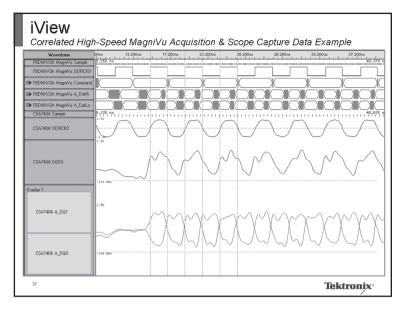


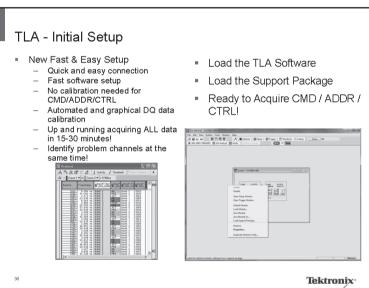


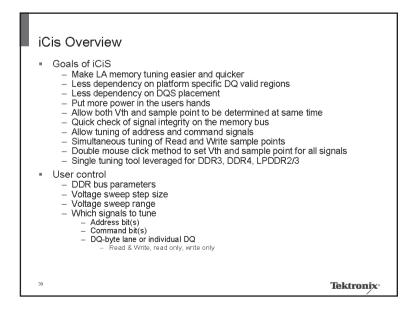




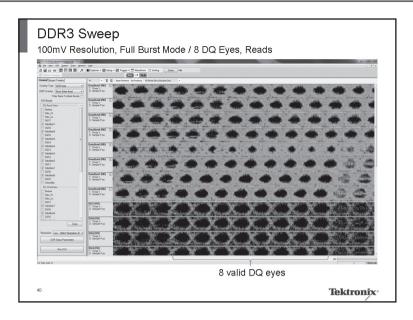


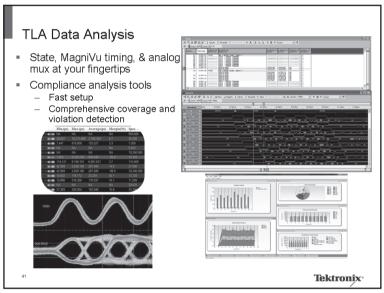


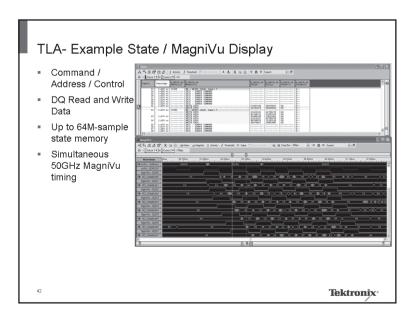




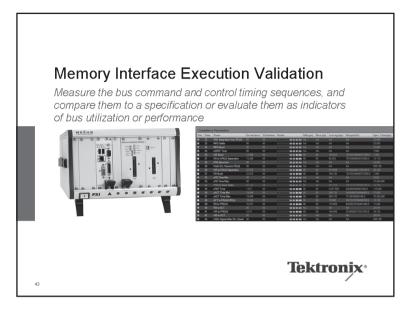












What's unique about Execution Validation

Typical instrument use a post-capture model

TRIGGER → ACQUIRE → ANALYZE

Execution Validation use model

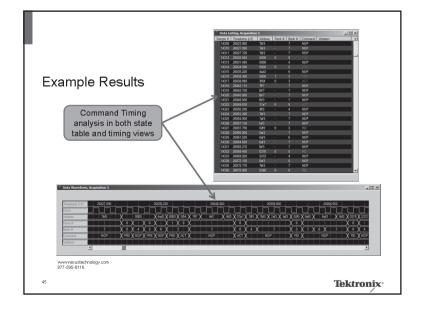
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Analysis Run

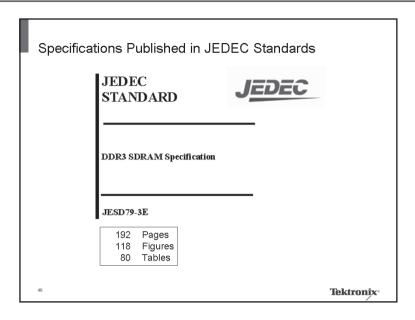
Two equipment options

1. Logic Analyzer - S/W automates acquisitions

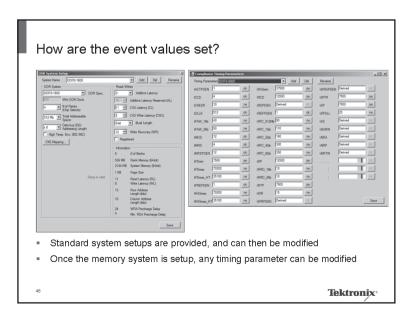
2. Memory Compliance Analyzer - Real-time Analysis



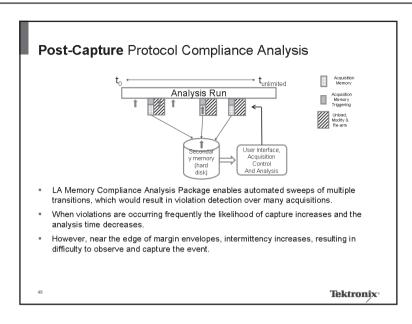


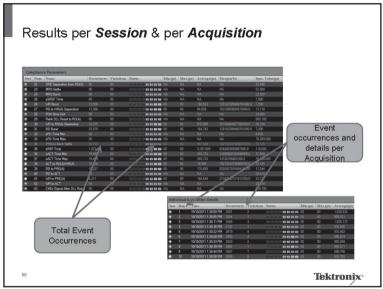


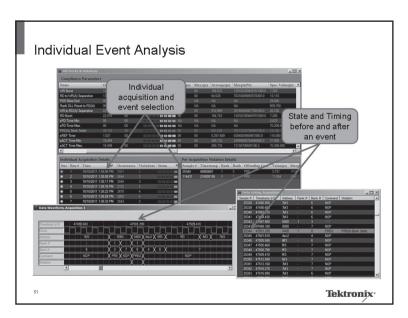


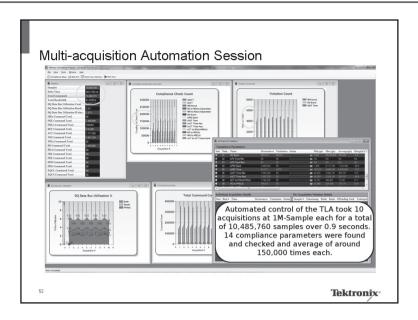


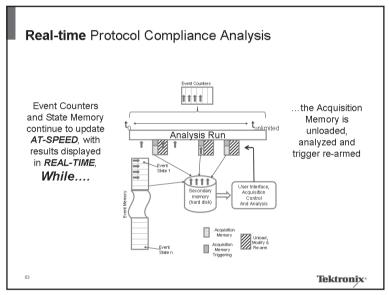


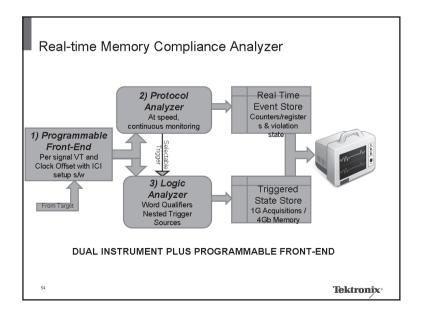














Memory Compliance Analyzer

REAL-TIME PROTOCOL COMPLIANCE ANALYSIS

- Analysis 160+ categories of JEDEC spec parameters
- Includes Power up/down, self-refresh and autoprecharge (RDA/WRA) analysis
- Timing and State analysis
- HTML reports / XML exporting

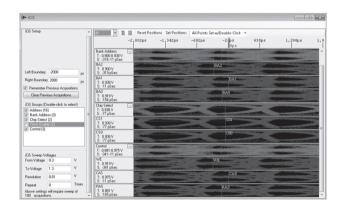


Real-time AND Post Capture Compliance Analysis

Command/Address

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Programmable Front-End / High Speed Eye Diagrams



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Automated Analysis Sessions

- One or Many Acquisitions / One or Both Analyzers
- Protocol Analysis Session
 - Protocol Analyzer runs until stopped
 - Violations and statistics are reported
- Single Acquisition Session
 - Protocol Analyzer runs until the state analyzer is triggered
 - Violations and statistics are reported.
 - State/Timing data is acquired and available for analysis
- Multi-Acquisition Session
 - Protocol Analyzer runs until the state analyzer is triggered
 - Results are stored in disk memory and analysis is restarted
 - Trigger conditions can be modified mid-session.

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